

74LVQ573

Low Voltage Octal Latch with 3-STATE Outputs

General Description

The LVQ573 is a high-speed octal latch with buffered common Latch Enable (LE) and buffered common Output Enable (\overline{OE}) inputs. The LVQ573 is functionally identical to the LVQ373 but with inputs and outputs on opposite sides of the package.

Features

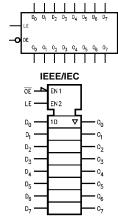
- Ideal for low power/low noise 3.3V applications
- Implements patented EMI reduction circuitry
- Available in SOIC JEDEC, SOIC EIAJ, and QSOP
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Improved latch-up immunity
- \blacksquare Guaranteed incident wave switching into 75 Ω
- 4 kV minimum ESD immunity

Ordering Code:

Onder Neuroleen	Daalaaa Noodaa	Declara Description
Order Number	Package Number	Package Description
74LVQ573SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
74LVQ573SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74LVQ573QSC	MQA20	20-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150" Wide

Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

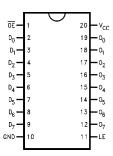
Logic Symbols



Pin Descriptions

Pin Names	Description
D ₀ –D ₇	Data Inputs
LE	Latch Enable Input
ŌĒ	3-STATE Output Enable Input
O ₀ -O ₇	3-STATE Latch Outputs

Connection Diagram



Truth Table

	Outputs			
ŌĒ	LE	D	O _n	
L	Н	Н	Н	
L	Н	L	L	
L	L	Х	O_0	
Н	X	Х	Z	
H = HIGH Voltage L = LOW Voltage				

H = HIGH Voltage Z = High Impedance

X = Immaterial

O₀ = Previous O₀ before HIGH-to-LOW transition of Latch Enable

© 2001 Fairchild Semiconductor Corporation

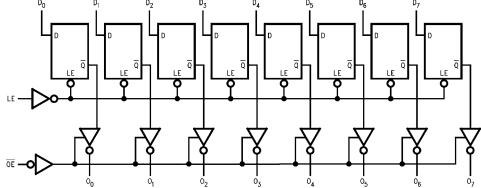
www.fairchildsemi.com

Functional Description

The LVQ573 contains eight D-type latches with 3-STATE output buffers. When the Latch Enable (LE) input is HIGH, data on the $D_{\rm n}$ inputs enters the latches. In this condition the latches are transparent, i.e., a latch output will change state each time its D-type input changes. When LE is LOW the latches store the information that was present on the

D-type inputs a setup time preceding the HIGH-to-LOW transition of LE. The 3-STATE buffers are controlled by the Output Enable (OE) input. When OE is LOW, the buffers are enabled. When OE is HIGH the buffers are in the high impedance mode but this does not interfere with entering new data into the latches.

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

Supply Voltage (V $_{CC}$) -0.5V to +7.0V

DC Input Diode Current (I_{IK})

 $\begin{array}{c} \text{V}_{\text{I}} = -0.5 \text{V} & -20 \text{ mA} \\ \text{V}_{\text{I}} = \text{V}_{\text{CC}} + 0.5 \text{V} & +20 \text{ mA} \\ \text{DC Input Voltage (V}_{\text{I}}) & -0.5 \text{V to V}_{\text{CC}} + 0.5 \text{V} \end{array}$

DC Output Diode Current (I_{OK})

 $V_O = -0.5V$ -20 mA

 $V_{O} = V_{CC} + 0.5V \\$ DC Output Voltage (V_O) $-0.5V \text{ to } V_{CC} + 0.5V$

DC Output Source

or Sink Current (I_O) $\pm 50 \text{ mA}$

DC V_{CC} or Ground

Current (I_{CC} or I_{GND}) ± 400 mA

Storage Temperature (T_{STG}) $-65^{\circ}C$ to $+150^{\circ}C$

DC Latch-Up Source or

Sink Current ±300 mA

Recommended Operating Conditions (Note 2)

Supply Voltage (V_{CC}) 2.0V to 3.6V

Minimum Input Edge Rate ($\Delta V/\Delta t$)

 V_{IN} from 0.8V to 2.0V

 $V_{CC} @ 3.0V$ 125 mV/ns

Note 1: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 2: Unused inputs must be held HIGH or LOW. They may not float.

DC Electrical Characteristics

Parameter	V_{CC} $T_A = +25^{\circ}C$		$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$	Unite	Conditions	
	(V) Typ Guarante		ranteed Limits	Onits	Conditions	
Minimum High Level	3.0	1.5	2.0	2.0	V	V _{OUT} = 0.1V
Input Voltage	3.0	1.5	2.0	2.0	v	or V _{CC} – 0.1V
Maximum Low Level	3.0	1.5	0.8	0.8	V	V _{OUT} = 0.1V
Input Voltage	0.0					or V _{CC} – 0.1V
Minimum High Level	3.0	2.99	2.9	2.9	٧	$I_{OUT} = -50 \mu A$
Output Voltage	3.0		2 58	2 48	V	$V_{IN} = V_{IL}$ or V_{IH} (Note 3)
	0.0		2.30	2.40	v	$I_{OH} = -12 \text{ mA}$
Maximum Low Level	3.0	0.002	0.1	0.1	V	$I_{OUT} = 50 \mu A$
Output Voltage	3.0		0.36	0.44	٧	V _{IN} = V _{IL} or V _{IH} (Note 3)
	3.0					I _{OL} = 12 mA
Maximum Input Leakage Current	3.6		±0.1	±1.0	μΑ	$V_I = V_{CC}$, GND
Minimum Dynamic	3.6			36	mA	$V_{OLD} = 0.8 V_{Max}$ (Note 5)
Output Current (Note 4)	3.6			-25	mA	$V_{OHD} = 2.0V V_{Min} (Note 5)$
I _{CC} Maximum Quiescent			4.0	40.0	υА	$V_{IN} = V_{CC}$
Supply Current	3.0			10.0	μ.	or GND
3-STATE						$V_{I}(\overline{OE}) = V_{IL}, V_{IH}$
Leakage Current	3.6		±0.25	±2.5	μА	$V_I = V_{CC}$, GND
						$V_O = V_{CC}$, GND
Quiet Output Maximum Dynamic V _{OL}	3.3	0.4	0.8		V	(Note 6)(Note 7)
Quiet Output Minimum Dynamic V _{OL}	3.3	-0.4	-0.8		٧	(Note 6)(Note 7)
Maximum High Level Dynamic Input Voltage	3.3	1.6	2.0		٧	(Note 6)(Note 8)
Maximum Low Level Dynamic Input Voltage	3.3	1.6	0.8		٧	(Note 6)(Note 8)
	Minimum High Level Input Voltage Maximum Low Level Input Voltage Minimum High Level Output Voltage Maximum Low Level Output Voltage Maximum Input Leakage Current Minimum Dynamic Output Current (Note 4) Maximum Quiescent Supply Current 3-STATE Leakage Current Quiet Output Maximum Dynamic V _{OL} Quiet Output Minimum Dynamic V _{OL} Maximum High Level Dynamic Input Voltage Maximum Low Level	Minimum High Level	Minimum High Level	Minimum High Level 3.0 1.5 2.0	Name	Name

 $\textbf{Note 3:} \ \textbf{All outputs loaded; thresholds on input associated with output under test.}$

 $\textbf{Note 4:} \ \ \textbf{Maximum test duration 2.0 ms, one output loaded at a time.}$

Note 5: Incident wave switching on transmission lines with impedances as low as 75Ω for commercial temperature range is guaranteed for.

Note 6: Worst case package.

Note 7: Max number of outputs defined as (n). Data inputs are driven 0V to 3.3V; one output at GND.

Note 8: Max number of Data Inputs (n) switching. (n - 1) inputs switching 0V to 3.3V. Input-under-test switching: 3.3V to threshold (V_{ILD}) , 0V to threshold (V_{IHD}) , f = 1 MHz.

www.fairchildsemi.com

AC Electrical Characteristics

				T _A = +25°C		T _A = -40°	C to +85°C	
Symbol	Parameter	V _{cc}	C _L = 50 pF			$C_L = 50 \text{ pF}$		Units
		(V)	Min	Тур	Max	Min	Max	
t _{PHL}	Propagation Delay	2.7	2.5	10.2	14.8	2.5	16.0	20
t _{PLH}	D _n to O _n	3.3 ± 0.3	2.5	8.5	10.5	2.5	11.0	ns
t _{PLH}	Propagation Delay	2.7	2.5	10.2	16.9	2.5	18.0	no
t _{PHL}	LE to O _n	3.3 ± 0.3	2.5	8.5	12.0	2.5	12.5	ns
t _{PZL}	Output Enable Time	2.7	2.5	10.2	18.3	2.5	19.0	
t _{PZH}		3.3 ± 0.3	2.5	8.5	13.0	2.5	13.5	ns
t _{PHZ}	Output Disable Time	2.7	1.0	10.8	20.4	1.0	21.0	no
t_{PLZ}		3.3 ± 0.3	1.0	9.0	14.5	1.0	15.0	ns
toshl	Output to Output Skew (Note 9)	2.7		1.0	1.5		1.5	ns
toslh	D _n to O _n	3.3 ± 0.3		1.0	1.5		1.5	115

Note 9: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}). Parameter guaranteed by design.

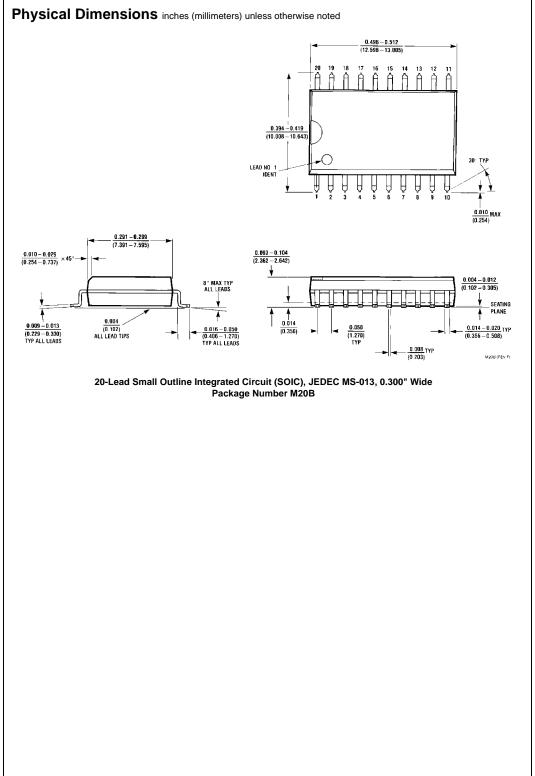
AC Operating Requirements

Symbol Parameter		V _{cc}	T _A = -	+25°C 50 pF	$T_A = -40$ °C to $+85$ °C $C_L = 50$ pF	Units	
		(V)	Тур	Guaran	teed Minimum		
t _S	Setup Time, HIGH or LOW	2.7	0	4.0	4.5	20	
	D _n to LE	3.3 ± 0.3	0	3.0	3.0	ns	
t _H	Hold Time, HIGH or LOW	2.7	0	1.5	1.5		
	D _n to LE	3.3 ± 0.3	0	1.5	1.5	ns	
t _W	LE Pulse Width, HIGH	2.7	2.4	5.0	6.0	no	
		3.3 ± 0.3	2.0	4.0	4.0	ns	

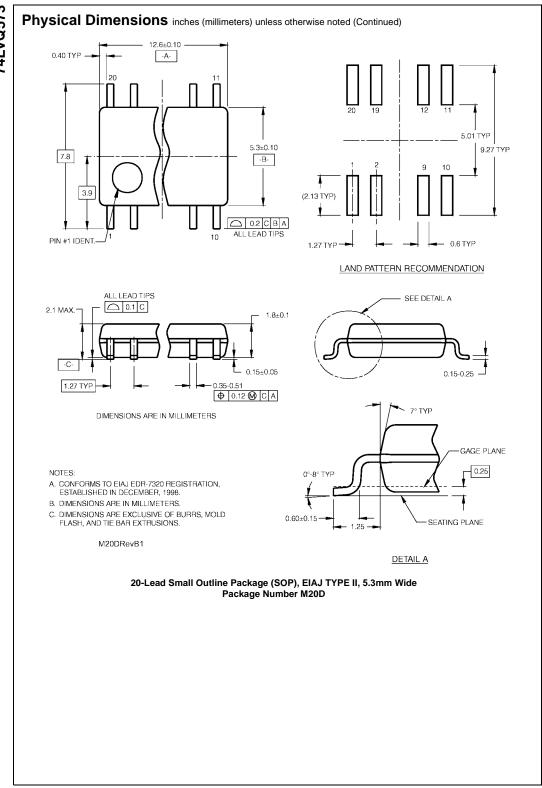
Capacitance

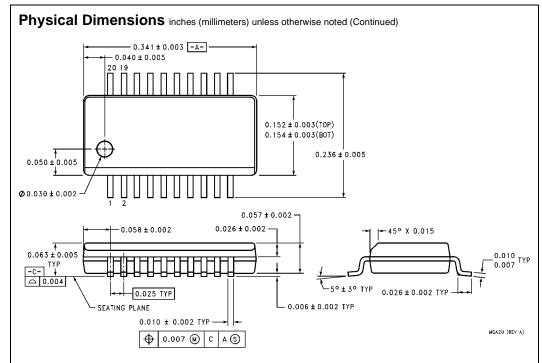
Symbol	Parameter	Тур	Units	Conditions
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = Open
C _{PD} (Note 10)	Power Dissipation Capacitance	37	pF	V _{CC} = 3.3V

Note 10: C_{PD} is measured at 10 MHz.









20-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150" Wide Package Number MQA20

Fairchild does not assume any responsibility for use of any circuitry described, no circuit patent licenses are implied and Fairchild reserves the right at any time without notice to change said circuitry and specifications.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
- A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

www.fairchildsemi.com